

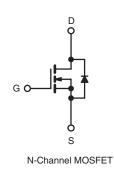
# N-Channel 60 V (D-S) MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	60				
R <sub>DS(on)</sub> (Ω)	$V_{GS} = 10 V$	0.027			
Q <sub>g</sub> (Max.) (nC)	95				
Q <sub>gs</sub> (nC)	27				
Q <sub>gd</sub> (nC)	46				
Configuration	Single				

### **FEATURES**

- Isolated Package
- High Voltage Isolation = 2.5 kV<sub>RMS</sub> (t = 60 s; f = 60 Hz)
- Sink to Lead Creepage Distance = 4.8 mm
- 175 °C Operating Temperature
- · Dynamic dV/dt Rating
- · Low Thermal Resistance
- Lead (Pb)-free Available





<b>ABSOLUTE MAXIMUM RATINGS</b> T	<sub>C</sub> = 25 °C, u	nless otherw	ise noted			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V <sub>DS</sub>	60	V		
Gate-Source Voltage			V <sub>GS</sub>			± 20
Continuous Drain Current	V <sub>GS</sub> at 10 V	$T_C = 25 °C$ $T_C = 100 °C$	I <sub>D</sub>	45		
		$T_C = 100 ^{\circ}C$		30	А	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	220		
Linear Derating Factor				0.32	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	E <sub>AS</sub> 100		
Maximum Power Dissipation	T <sub>C</sub> = 25 °C		P <sub>D</sub> 52		W	
Peak Diode Recovery dV/dt <sup>c</sup>			dV/dt	4.5	V/ns	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 175	°C		
Soldering Recommendations (Peak Temperature)	for 10 s			300 <sup>d</sup>		
Mounting Torque	6 32 or 1	6-32 or M3 screw		10	lbf ⋅ in	
	0-32 OF IVI3 SCIEW			1.1	N · m	

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b.  $V_{DD} = 25 \text{ V}$ , starting  $T_J = 25 \text{ °C}$ , L = 129  $\mu$ H,  $R_G = 25 \Omega$ ,  $I_{AS} = 30 \text{ A}$  (see fig. 12). c.  $I_{SD} \leq 52 \text{ A}$ , dI/dt  $\leq 250 \text{ A}/\mu$ s,  $V_{DD} \leq V_{DS}$ ,  $T_J \leq 175 \text{ °C}$ .

d. 1.6 mm from case.



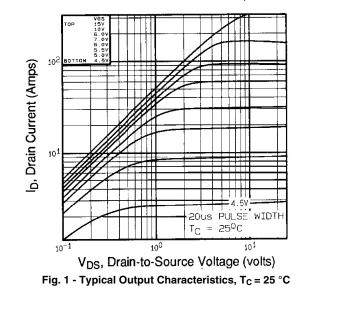


THERMAL RESISTANCE RAT	FINGS								
PARAMETER	SYMBOL	TYP. MAX.			UNIT				
Maximum Junction-to-Ambient	R <sub>thJA</sub>	- 65			°CAN				
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	- 3.1				°C/W			
<b>SPECIFICATIONS</b> $T_J = 25 \degree C$ ,	uplace other	vice noted							
PARAMETER	SYMBOL			ONS	MIN.	TYP.	MAX.	UNIT	
Static	STWDOL	TES	CONDITI	0113	IVIIIN.	116.	WAA.	UNIT	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	Vee	- 0 \/   2	50	60	-	-	V	
V <sub>DS</sub> Temperature Coefficient	ΔV <sub>DS</sub> /TJ	$V_{GS} = 0 \text{ V}, \text{ I}_D = 250 \mu\text{A}$				0.060	-	v/∘C	
Gate-Source Threshold Voltage		Reference to 25 °C, $I_D = 1 \text{ mA}$			1.0	-	3.0	V	
Gate-Source Leakage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$			1.0	-	± 100		
Gale-Source Leakage	I <sub>GSS</sub>	$V_{GS} = \pm 20 V$			-	-		nA μA	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	_	$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}$			-	25 250		
Drain-Source On-State Resistance	<b>D</b>	$V_{DS} = 48 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 150 \text{ °C}$ $V_{GS} = 10 \text{ V} \qquad I_{D} = 18 \text{ A}^{b}$			-	0.027	- 250		
Forward Transconductance	R <sub>DS(on)</sub>	$V_{GS} = 10 V$			- 15	0.027	_	Ω S	
Dynamic	9 <sub>fs</sub>	VDS -	= 25 V, I <sub>D</sub> =	10 A*	15	-	[ -	3	
-	<u> </u>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 25 V, f = 1.0 MHz, see fig. 5		-	1500	-	pF		
Input Capacitance	Ciss				1500				
Output Capacitance	C <sub>oss</sub>			-	720	-			
Reverse Transfer Capacitance	C <sub>rss</sub>			-	100				
Drain to Sink Capacitance	C		f = 1.0 MHz	2	-	12	-		
Total Gate Charge	Qg		I <sub>D</sub> = 52 A, V <sub>DS</sub> = 48 V,	-	-	95	nC		
Gate-Source Charge	Q <sub>gs</sub>		e fig. 6 and 13 <sup>b</sup>	-	-	27			
Gate-Drain Charge	$Q_{gd}$				-	-	46		
Turn-On Delay Time	t <sub>d(on)</sub>	$\begin{split} V_{DD} &= 30 \text{ V}, \text{ I}_{D} = 52 \text{ A}, \\ R_{G} &= 9.1 \ \Omega, \ R_{D} = 0.54 \ \Omega, \\ \text{see fig. } 10^{\text{b}} \end{split}$		-	19	-	- ns		
Rise Time	t <sub>r</sub>			-	120	-			
Turn-Off Delay Time	t <sub>d(off)</sub>			-	55	-			
Fall Time	t <sub>f</sub>				-	86	-		
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	nH		
Internal Source Inductance	Ls			-	7.5	-			
Drain-Source Body Diode Characteristic	s						l.		
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	45	A		
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	120			
Body Diode Voltage	V <sub>SD</sub>	$T_{\rm J}$ = 25 °C, I <sub>S</sub> = 30 A, V <sub>GS</sub> = 0 V <sup>b</sup>		-	-	2.5	V		
Body Diode Reverse Recovery Time	t <sub>rr</sub>	$T_J = 25 \text{ °C}, I_F = 52 \text{ A}, dI/dt = 100 \text{ A}/\mu \text{s}^{b}$		-	140	300	ns		
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	1.2	2.8	μC		
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S$ and $L_{\Gamma}$					)		

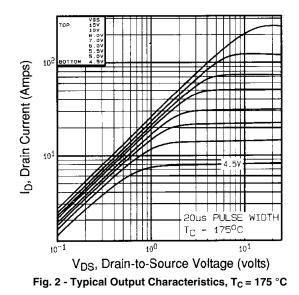
#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width  $\leq$  300 µs; duty cycle  $\leq$  2 %.









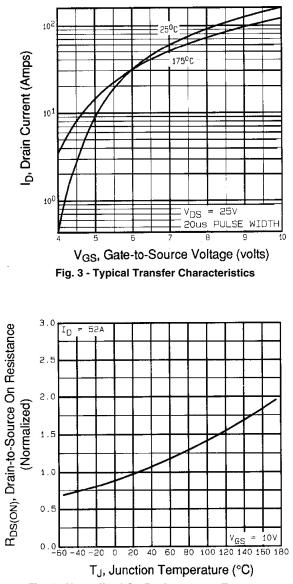


Fig. 4 - Normalized On-Resistance vs. Temperature

### **IRFIZ24GP**



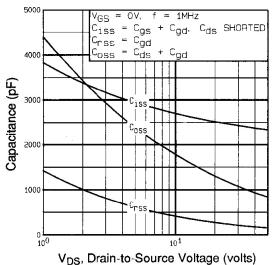


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

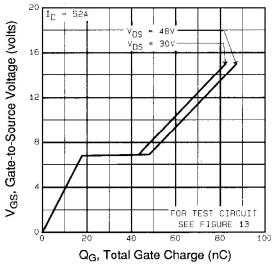


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

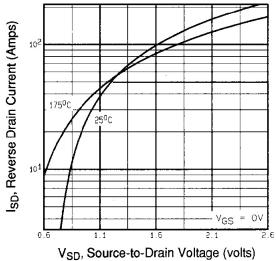
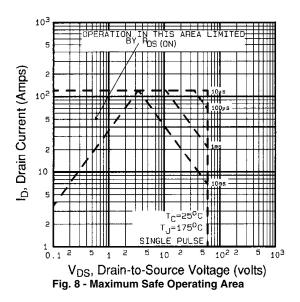


Fig. 7 - Typical Source-Drain Diode Forward Voltage





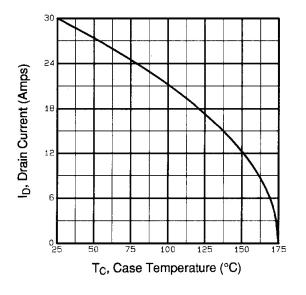


Fig. 9 - Maximum Drain Current vs. Case Temperature

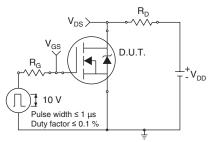


Fig. 10a - Switching Time Test Circuit

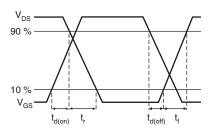


Fig. 10b - Switching Time Waveforms

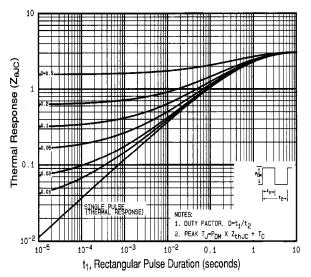


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

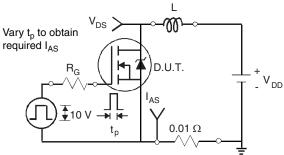


Fig. 12a - Unclamped Inductive Test Circuit

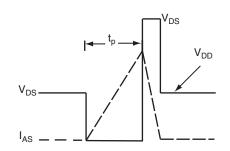
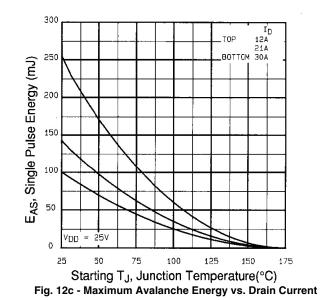
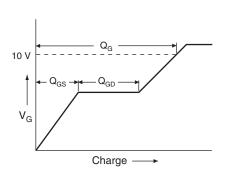


Fig. 12b - Unclamped Inductive Waveforms







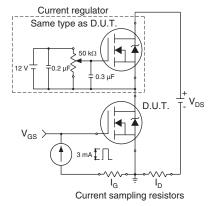
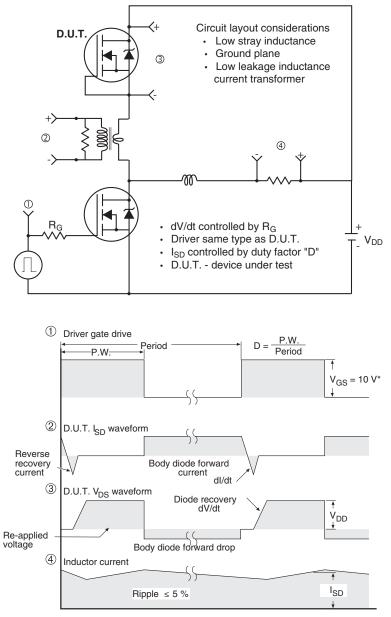


Fig. 13a - Basic Gate Charge Waveform

Fig. 13b - Gate Charge Test Circuit





### Peak Diode Recovery dV/dt Test Circuit

\*  $V_{GS}$  = 5 V for logic level devices

Fig. 14 - For N-Channel



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